

TLP250(INV)

TRANSISTOR INVERTER INVERTERS FOR AIR CONDITIONER IGBT GATE DRIVE POWER MOS FET GATE DRIVE

The TOSHIBA TLP250(INV) consists of a GaAlAs light emitting diode and a integrated photodetector.

This unit is 8-lead DIP.

TLP250(INV) is suitable for gate driving circuit of IGBT or power MOS FET.

- Input Threshold Current : $I_F=5\text{mA}(\text{MAX})$
- Supply Current(I_{CC}) : $11\text{mA}(\text{MAX})$
- Supply Voltage(V_{CC}) : $10\sim 35\text{V}$
- Output Current(I_O) : $\pm 2.0\text{A}(\text{MAX})$
- Switching Time(t_{pLH}/t_{pHL}) : $0.5\mu\text{s}(\text{MAX})$
- Isolation Voltage : $2500\text{V}_{\text{rms}}$
- UL Recognized : UL1577,File No.E67349
- Option(D4)

VDE Approved : DIN VDE0884/06.92 Certificate No.76823

Maximum Operating Insulation Voltage : 630V_{PK}

Highest Permissible Over Voltage : 4000V_{PK}

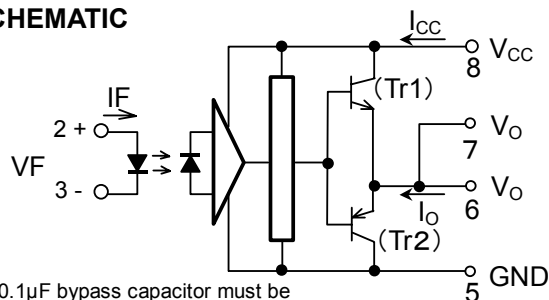
**(Note):When a VDE0884 approved type is needed,
Please designate the "Option(D4)"**

- Creepage Distance : $6.4\text{mm}(\text{MIN})$
- Clearance : $6.4\text{mm}(\text{MIN})$

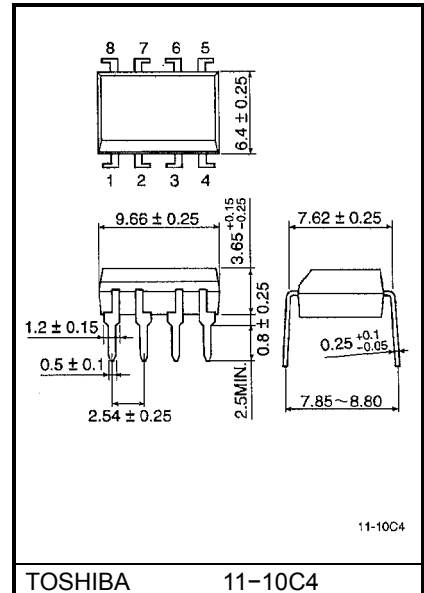
TRUTH TABLE

		Tr 1	Tr 2
INPUT LED	ON	ON	OFF
	OFF	OFF	ON

SCHEMATIC

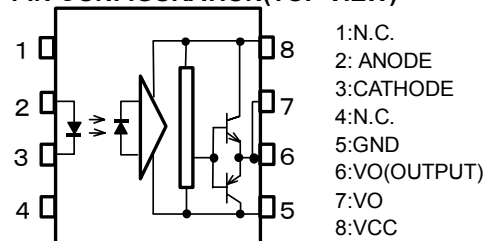


Unit in mm



Weight: 0.54 g

PIN CONFIGURATION(TOP VIEW)



MAXIMUM RATINGS (Ta=25°C)

CHARACTERISTIC				SYMBOL	RATING	UNIT	
LED	Forward Current			I _F	20	mA	
	Forward Current Derating (Ta≥70℃)			ΔI _F /ΔTa	−0.36	mA /℃	
	Peak Transient Forward Current (Note 1)			I _{FPT}	1	A	
	Reverse Voltage			V _R	5	V	
	Junction Temperature			T _j	125	℃	
DETECTOR	“H” Peak Output Current		PW ≤2.5μs , f≤15 kHz	(Note 2)	I _{OPH}	−1.5	A
			PW≤1.0μs , f≤15 kHz			−2.0	
	“L” Peak Output Current		PW≤2.5μs , f≤15 kHz		I _{OPL}	+1.5	A
			PW ≤1.0μs , f≤15 kHz			+2.0	
	Output Voltage		(Ta≤70℃)	V _O	35	V	
			(Ta=85℃)		24		
	Supply Voltage		(Ta≤70℃)	V _{CC}	35	V	
			(Ta=85℃)		24		
	Output Voltage Derating (Ta≥70℃)			ΔV _O /ΔTa	−0.73	V /℃	
	Supply Voltage Derating (Ta≥70℃)			ΔV _{CC} /ΔTa	−0.73	V /℃	
	Junction Temperature			T _j	125	℃	
Operating Frequency (Note 3)				f	25	kHz	
Operating Temperature Range				T _{opr}	−20~85	℃	
Storage Temperature Range				T _{stg}	−55~125	℃	
Lead Soldering Temperature(10s)				T _{sol}	260	℃	
Isolation Voltage (AC,1min., R.H. ≤60%,Ta=25℃) (Note 4)				BV _S	2500	Vrms	

(Note 1) : Pulse width PW≤1μs,300pps

(Note 2) : Exponential Waveform

(Note 3) : Exponential Waveform $I_{OPH} \leq -1.0A (\leq 2.5\mu s)$, $I_{OPL} \leq +1.0A (\leq 2.5\mu s)$

(Note 4) : Device considered a two terminal device : pins 1,2,3 and 4 shorted together and pins 5,6,7 and 8 shorted together.

(Note 5) : A ceramic capacitor(0.1μF) should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier.Failure to provide the bypassing may impair the switching property.The total lead length between capacitor and coupler should not exceed 1cm.

RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	MIN	TYP.	MAX	UNIT
Input Current, ON	$I_{F(ON)}$	7	8	10	mA
Input Voltage, OFF	$V_{F(OFF)}$	0	—	0.8	V
Supply Voltage	V_{CC}	15	—	30 20	V
Peak Output Current	I_{OPH} / I_{OPL}	—	—	±0.5	A
Operating Temperature	T_{opr}	-20	25	70 85	°C

ELECTRICAL CHARACTERISTICS (Ta = -20~70°C, Unless otherwise specified)

CHARACTERISTIC		SYMBOL	TEST CIRCUIT	TEST CONDITION		MIN	TYP.	MAX	UNIT
Input Forward Voltage		V _F	—	I _F = 10 mA, Ta = 25°C		—	1.6	1.8	V
Temperature Coefficient of Forward Voltage		ΔV _F / ΔTa	—	I _F = 10 mA		—	-2.0	—	mV /°C
Input Reverse Current		I _R	—	V _R = 5 V, Ta = 25°C		—	—	10	μA
Input Capacitance		C _T	—	V = 0, f = 1 MHz, Ta = 25°C		—	45	250	pF
Output Current	“H” Level	I _{OPH}	2	V _{CC} = 30 V (*1)	I _F = 10 mA V ₈₋₆ = 4 V	-1.0	-1.5	—	A
	“L” Level	I _{OPL}	1		I _F = 0 V ₆₋₅ = 2.5 V	1.0	2	—	
Output Voltage	“H” Level	V _{OH}	3	V _{CC1} = +15 V V _{EE1} = -15 V R _L = 200Ω, I _F = 5 mA		11	12.8	—	V
	“L” Level	V _{OL}	4	V _{CC1} = +15 V V _{EE1} = -15 V R _L = 200Ω, V _F = 0.8 V		—	-14.2	-12.5	
Supply Current	“H” Level	I _{CCH}	—	V _{CC} = 30 V	I _F = 10 mA Ta = 25°C	—	7	—	mA
					I _F = 10 mA	—	—	11	
	“L” Level	I _{CCL}	—		I _F = 0 mA Ta = 25°C	—	7.5	—	mA
					I _F = 0 mA	—	—	11	
Threshold Input Current	L→H	I _{FLH}	—	V _{CC1} = +15 V V _{EE1} = -15 V R _L = 200Ω, V _O > 0V		—	1.2	5	mA
Threshold Input Voltage	H→L	V _{FHL}		V _{CC1} = +15 V V _{EE1} = -15 V R _L = 200Ω, V _O < 0V		0.8	—	—	V
Supply Voltage		V _{CC}	—	—		10	—	35	V
Capacitance (Input-Output)		C _S	—	V _S = 0, f = 1 MHz, Ta = 25°C		—	1.0	2.0	pF
Resistance (Input-Output)		R _S	—	V _S = 500 V, Ta = 25°C R.H.≤60%		1×10 ¹²	10 ¹⁴	—	Ω

(*) : All typical values are at $T_a = 25^\circ\text{C}$

(*1) : Duration of IO time ≤ 50μs

SWITCHING CHARACTERISTICS (Ta = -20~70°C, Unless otherwise specified)

CHARACTERISTIC		SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
Propagation Delay Time	L→H	t_{pLH}	5	$I_F = 8\text{ mA}$, $V_{CC} = 15\text{ V}$ $R_L = 20\Omega$, $C_L = 10\text{ nF}$	0.05	0.15	0.5	μs
	H→L	t_{pHL}			0.05	0.15	0.5	
Switching Time Dispersion between ON and OFF		$ t_{pHL}-t_{pLH} $			—	—	0.45	
Output Rise Time		t_r			—	—	—	
Output Fall Time		t_f			—	—	—	
Common Mode Transient Immunity at High Level Output		CM_H	6	$V_{CM} = 1000\text{ V}$, $I_F = 8\text{ mA}$ $V_{CC} = 30\text{ V}$, $T_a = 25^\circ\text{C}$	-15000	—	—	$\text{V}/\mu\text{s}$
Common Mode Transient Immunity at Low Level Output		CM_L		$V_{CM} = 1000\text{ V}$, $I_F = 0\text{ mA}$ $V_{CC} = 30\text{ V}$, $T_a = 25^\circ\text{C}$	15000	—	—	$\text{V}/\mu\text{s}$

Fig.1 I_{OPL} TEST CIRCUIT

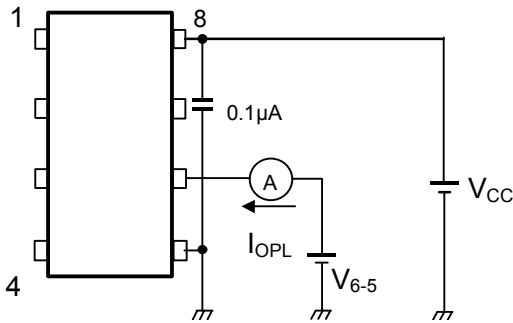


Fig.2 I_{OPH} TEST CIRCUIT

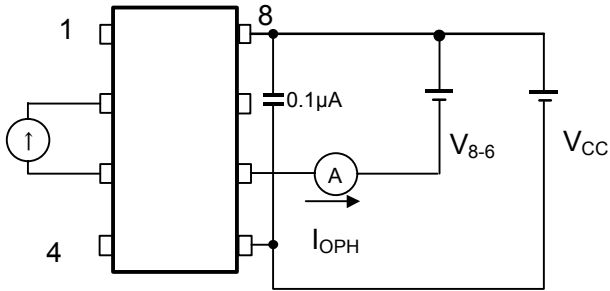


Fig.3 V_{OH} TEST CIRCUIT

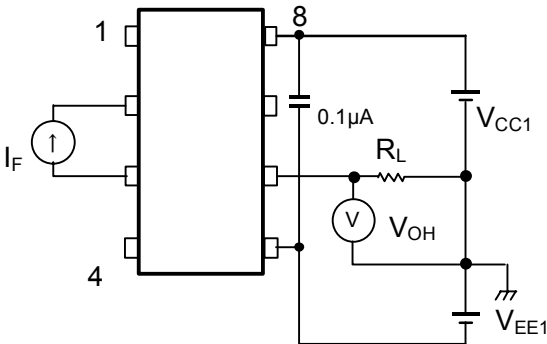


Fig.4 V_{OL} TEST CIRCUIT

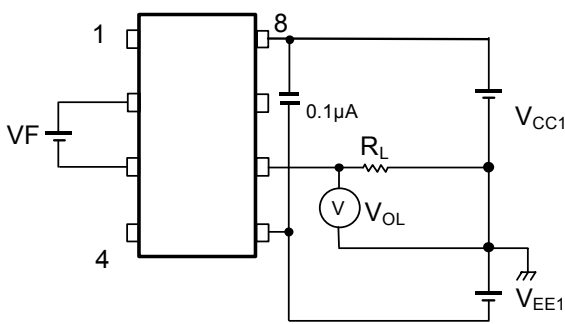


Fig.5 t_{pLH} , t_{pHL} , t_r , t_f TEST CIRCUIT

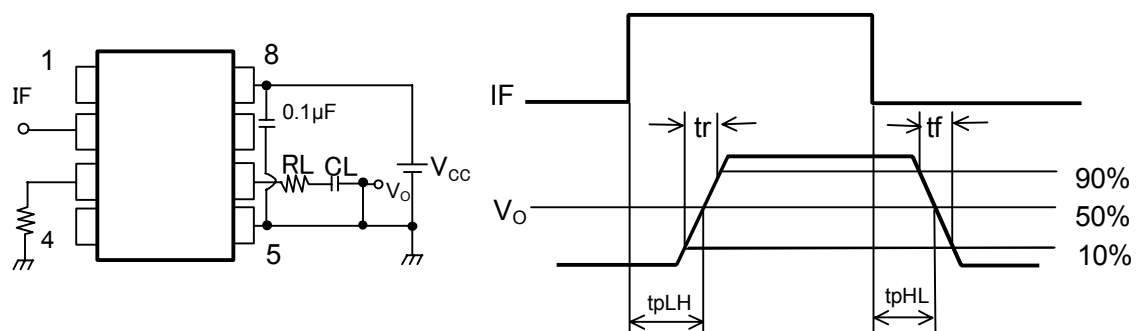
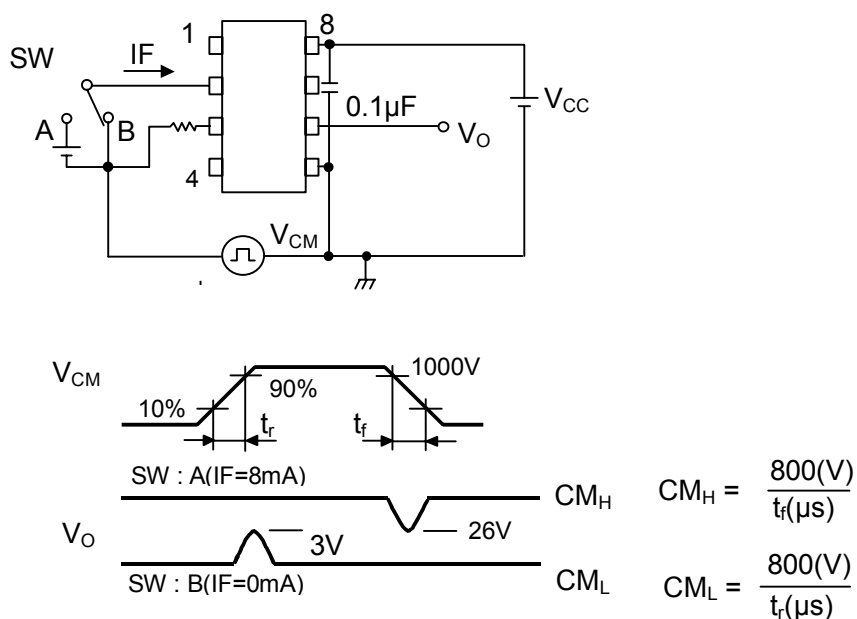


Fig.6 CM_H , CM_L TEST CIRCUIT



$CM_L(CM_H)$ is the maximum rate of rise(fall) of the common mode voltage that can be sustained with the output voltage in the low(high)state.

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